

October 2006

# FDS8949

# Dual N-Channel Logic Level PowerTrench® MOSFET 40V, 6A, 29mΩ

#### **Features**

- Max  $r_{DS(on)} = 29m\Omega$  at  $V_{GS} = 10V$
- Max  $r_{DS(on)} = 36m\Omega$  at  $V_{GS} = 4.5V$
- Low gate charge
- High performance trench technology for extremely low rDS(on)
- High power and current handling capability
- RoHS compliant



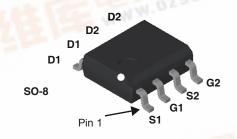
#### **General Description**

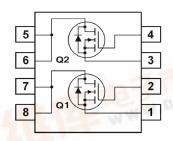
These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

#### **Applications**

- Inverter
- Power suppliers





# MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	ymbol Parameter		Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage		40	V	
V <sub>GS</sub>	Gate to Source Voltage		±20	V	
Drain Current -Continuous (Note		(Note 1a)	6	^	
ID	-Pulsed		20	A	
E <sub>AS</sub>	Drain-Source Avalanche Energy	(Note 3)	26	mJ	
	Power Dissipation for Dual Operation		2	125	
$P_{D}$	Power Dissipation for Single Operation	(Note 1a)	1.6	W	
	33	(Note 1b)	0.9		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to 150	°C	

## **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance-Single operation, Junction to Ambient	(Note 1a)	81	
$R_{\theta JA}$	Thermal Resistance-Single operation, Junction to Ambient	(Note 1b)	135	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	40	

# Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDS8949	FDS8949	13"	12mm	2500 units

<b>Electrical Characteristics</b>	T <sub>J</sub> = 25°C unless otherwise noted
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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0V$	40			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		33		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 32V, V_{GS} = 0V$ $T_1 = 55^{\circ}C$			1	μ <b>Α</b> μ <b>Α</b>
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nΑ

#### On Characteristics (Note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1	1.9	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C		-4.6		mV/°C
		$V_{GS} = 10V, I_D = 6A$		21	29	
r <sub>DS(on)</sub>	Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 4.5A$		26	36	$m\Omega$
		$V_{GS} = 10V, I_D = 6A, T_J = 125$ °C		29	43	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10V, I_D = 6A$		22		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance		715	955	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, f = 1MHz	105	140	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11VII 12	60	90	pF
$R_g$	Gate Resistance	f = 1MHz	1.1		Ω

#### **Switching Characteristics**

	•				
$t_{d(on)}$	Turn-On Delay Time	.,	9	18	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 20V, I_{D} = 1A$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	5	10	ns
$t_{d(off)}$	Turn-Off Delay Time	VGS = 10V, NGEN = 052	23	37	ns
$t_f$	Fall Time		3	6	ns
$Q_g$	Total Gate Charge		7.7	11	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 20V, I_D = 6A, V_{GS} = 5V$	2.4		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		2.8		nC

## **Drain-Source Diode Characteristics** and Maximum Ratings

$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 6A (note 2)	0.8	1.2	V
t <sub>rr</sub>	Reverse Recovery Time (note 3)	$I_F = 6A, d_{iF}/d_t = 100A/\mu s$	17	26	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1F - 0A, u <sub>i</sub> F/u <sub>t</sub> - 100A/μs	7	11	nC

#### Notes

1:  $R_{BJA}$  is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{BJC}$  is guaranteed by design while  $R_{BJA}$  is determined by the user's board design.



a) 81°C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper

Scale 1:1 on letter size paper



**b)**  $135^{\circ}\text{C/W}$  when mounted on a minimum pad .

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2: Pulse Test: Pulse Width < 300 us, Duty Cycle < 2.0%.

3: Starting  $T_J$  = 25°C, L = 1mH,  $I_{AS}$  = 7.3A,  $V_{DD}$  = 40V,  $V_{GS}$  = 10V.

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

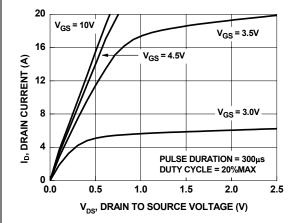


Figure 1. On Region Characteristics

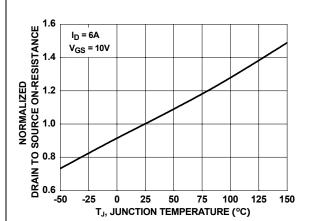


Figure 3. Normalized On Resistance vs Junction Temperature

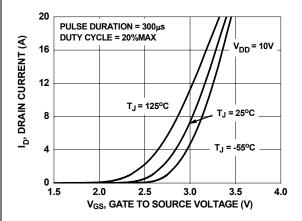


Figure 5. Transfer Characteristics

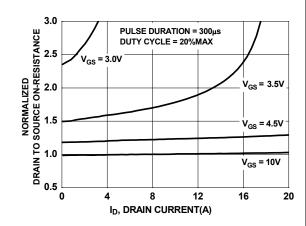


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

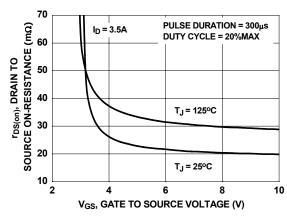


Figure 4. On-Resistance vs Gate to Source Voltage

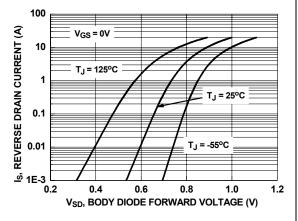


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

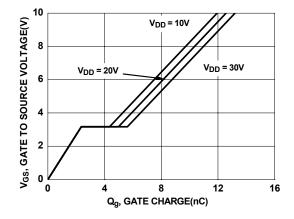


Figure 7. Gate Charge Characteristics

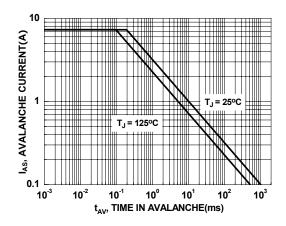


Figure 9. Unclamped Inductive Switching Capability

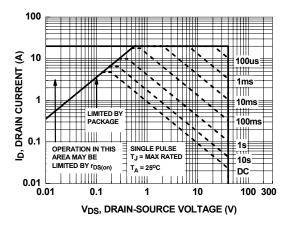


Figure 11. Forward Bias Safe Operating Area

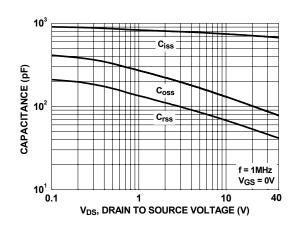


Figure 8. Capacitance vs Drain to Source Voltage

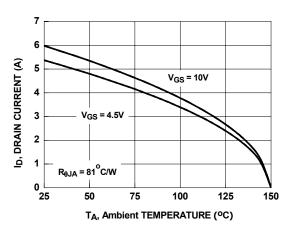


Figure 10. Maximum Continuous Drain Current vs
Ambient Temperature

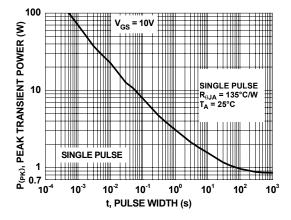


Figure 12. Single Pulse Maximum Power Dissipation

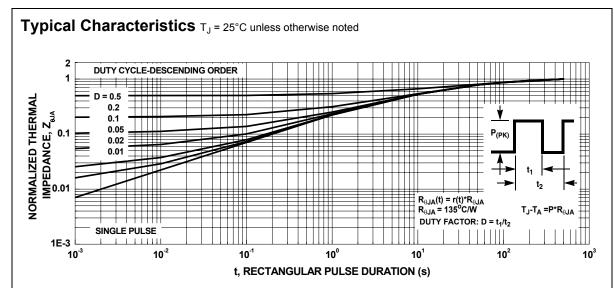


Figure 13. Transient Thermal Response Curve

UniFET™ UltraFET®  $VCX^{TM}$ Wire™

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